

Supporting information for

Orthogonal Binary Cations Arrangement Homogenizing Interfacial Coordination and Electronic Landscapes for High Performance Perovskite Solar Cells

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Experimental Section

Materials

Lead (II) iodide (PbI_2 , 99.99%) and Me-2PACz (99%) were obtained from TCI. Formamidinium iodide (FAI), methylammonium chloride (MACl, 99.5%), and methylammonium iodide (MAI) were purchased from Greatcell Solar Ltd. Solvents, including N,N-dimethylformamide (DMF, anhydrous, 99.8%), dimethyl sulfoxide (DMSO, anhydrous, 99.8%), and isopropanol (IPA, 99.5%), were acquired from J&K Scientific Ltd. Nickel oxide (NiO_x) and ITO glass substrates were sourced from Advanced Electronic Technology Co., Ltd., while silver was obtained from ZhongNuo Advanced Material Technology Co., Ltd. PEAI and EDAI_2 were purchased from Aladdin Scientific. All materials were used without further purification.

Perovskite Solar Cell Fabrication

ITO substrates were cleaned sequentially by sonication in detergent, deionized water, acetone, and isopropyl alcohol for 20 minutes each, followed by ultraviolet-ozone treatment for 30 minutes. A NiO_x solution (10 mg mL^{-1} in deionized water) was spin-coated onto the cleaned ITO substrates at 2,000 rpm for 30 seconds in ambient air and annealed at $150 \text{ }^\circ\text{C}$ for 15 minutes. Subsequently, a Me-2PACz solution (0.8 mg mL^{-1} in isopropanol) was spin-coated onto the NiO_x layer at 5,000 rpm for 30 seconds and annealed at $100 \text{ }^\circ\text{C}$ for 10 minutes. For perovskite precursor preparation, a 1.5 M solution was formulated by dissolving 19.5 mg of CsI, 219.3 mg of FAI, 23.8 mg of MAI, and 760.7 mg of PbI_2 (with 10% excess) in 1 mL of DMF: DMSO (4:1 v/v) mixed solvent, yielding a composition of $\text{Cs}_{0.05}\text{FA}_{0.85}\text{MA}_{0.1}\text{PbI}_3$ with a bandgap of 1.55 eV. A

1.4 M solution was prepared by dissolving 18.2 mg of CsI, 192.6 mg of FAI, 536 mg of PbI₂ (with 10% excess), 131 mg of PbBr₂, and 23.5 mg of MABr in 1 mL of DMF:DMSO (4:1 v/v) mixed solvent, resulting in Cs_{0.05}FA_{0.8}MA_{0.15}Pb(I_{0.76}Br_{0.24})₃ with a bandgap of 1.68 eV. To improve crystallization and reduce bulk defects, 12.5 mol% MACl was added to the precursor solutions for all bandgaps and stirred for 2 hours. All procedures were performed in a nitrogen-filled glovebox. For 1.55 eV perovskite films, the precursor was spin-coated onto substrates with the hole transport layer at 1,000 rpm for 10 seconds, followed by 5,000 rpm for 40 seconds, with 200 μL of chlorobenzene dripped onto the film center 5 seconds before the end of spin-coating. The substrates were then annealed at 100 °C for 30 minutes.

For 1.68 eV perovskite films, the precursor was spin-coated at 1,000 rpm for 5 seconds, followed by 5,000 rpm for 30 seconds, with 200 μL of chlorobenzene added 15 seconds before the end. Annealing was conducted at 100 °C for 15 minutes.

For two-step perovskite deposition, a 1.5 M PbI₂ solution in DMF/DMSO (9:1 v/v) was stirred for 120 minutes, filtered, and spin-coated onto the hole transport layer at 2,000 rpm for 20 seconds. A filtered organic salt solution in IPA (FAI: MAI: MACl = 90:6.4:9 mg mL⁻¹) was then spin-coated at 2,500 rpm for 30 seconds at room temperature, followed by annealing at 100 °C for 25 minutes.

Materials and device characterizations

UV-vis absorption spectra were measured using a Shimadzu UV-1800 spectrophotometer. Sum frequency generation (SFG) spectra were acquired using a

commercial SFG spectrometer (SFGPL2230, EKSPLA Co., Lithuania). The visible and tunable infrared (IR) laser pulses were overlapped both spatially and temporally at the sample surface, with incidence angles of 60° and 55° (relative to the surface normal), respectively. The visible pump beam had a fixed wavelength of 532 nm. The IR beam was scanned across the fingerprint and functional group regions from 1000 to 3500 cm^{-1} . The spectral resolution of the system was 5 cm^{-1} . Spectra were collected under two distinct polarization combinations: ssp (i.e., s-polarized SFG, s-polarized visible, and p-polarized IR) and ppp (i.e., p-polarized SFG, p-polarized visible, and p-polarized IR). The passivated perovskite films were fabricated with a thickness of ~ 800 nm to ensure they were thick enough to eliminate any interference signals from the underlying substrate. XRD was acquired with a Rigaku Ultima IV diffractometer. SEM images and device cross-sections were obtained using a Zeiss Merlin Compact field-emission scanning electron microscope. XPS was performed on a Thermo Fisher ESCALab 250Xi system. AFM and KPFM were conducted using a Bruker MM8 instrument. Steady-state and time-resolved PL spectra were measured with a 420 nm picosecond laser on a PicoQuant FluoTime 300 system. PLQY was determined with 405 nm excitation under integrating sphere mode. In situ PL spectra were acquired using a QE6500 spectrometer (Ocean Optics) in a nitrogen glovebox with 355 nm excitation. Current-voltage curves (forward scan from -0.2 to 1.2 V; reverse scan from 1.2 to -0.2 V) were obtained under AM 1.5G illumination (100 mW cm^{-2}) using a solar simulator and Keithley 2400 source meter. EIS, SCLC, and Mott-Schottky analyses were performed with a CHI660E electrochemical workstation under ambient conditions.

Long-term operational stability was evaluated according to the ISOS-L-2I protocol. Devices were encapsulated using cover glass (1.1 mm) and NOA61 adhesive (Norland Products Inc.). The encapsulated devices were tested under one-sun equivalent LED illumination in a nitrogen-filled glovebox. Devices were biased at the maximum power point using an electronic load, with power output monitored. The test temperature was maintained at 65 °C, and the device temperature was periodically checked with a thermometer.

Theoretical Calculations

ESP was conducted at the B3LYP/6-31+G(d,p) level using Gaussian 09. Density functional theory calculations were performed with the CP2K package via its Quickstep module, employing a mixed Gaussian and plane-wave approach. The Perdew-Burke-Ernzerhof functional within the generalized gradient approximation was used, with dispersion corrections via Grimme's DFT-D3 method and Becke-Johnson damping. Models were based on a $7 \times 7 \times 3$ supercell slab of PbI_2 -terminated FAPbI_3 (001). For the OrthBC configuration, PEA^+ and EDA^{2+} cations were added in a 4:1 molar ratio; ParaC and PerpC arrangements were constructed similarly for comparison. Binding energies were calculated as $E_{\text{ads}} = E(\text{slab@molecule}) - E(\text{slab}) - E(\text{molecule})$.

Supplementary Note 1

Space charge limited current (SCLC) measurement

The trap density (N_t) of the perovskite is calculated using SCLC measurement. The N_t were calculated as follows:¹

$$N_t = \frac{2\varepsilon_r\varepsilon_0V_{TFL}}{qd^2}$$

where ε_0 , ε_r , d , and q represent the vacuum permittivity (8.854×10^{-14} F/cm), the relative permittivity of perovskite films, the thickness of the perovskite film (≈ 830 nm), and the elementary charge (1.602×10^{-19} C), respectively.

Supplementary Note 2

Time-Resolved Photoluminescence (TRPL)

To probe the carrier recombination dynamics in the control, reference, and target perovskite films, TRPL decay profiles were acquired and fitted using a biexponential decay model:²

$$Y = A_1 \exp\left(-\frac{t}{\tau_1}\right) + A_2 \exp\left(-\frac{t}{\tau_2}\right),$$

where A_1 and A_2 are the relative amplitudes of the two decay components. The fast decay time constant τ_1 is associated with radiative recombination, while the slow decay constant τ_2 reflects trap-assisted nonradiative recombination processes. The average

carrier lifetime τ_{avg} was calculated as $\tau_{\text{avg}} = \frac{A_1\tau_1^2 + A_2\tau_2^2}{A_1\tau_1 + A_2\tau_2}$

Supplementary Note 3

Calculation of the quasi-Fermi level splitting (QFLS) based on the PL quantum yield (PLQY)

The photoluminescence quantum yield (PLQY) bears a direct correlation with the quasi-Fermi level splitting (QFLS), provided that all PL emission originates from the radiative recombination of free charge carriers in the perovskite film. This relationship can be described by the equation below:³

$$QFLS = QFLS_{rad} + k_B T \cdot \ln(PLQY) = k_B T \cdot \ln\left(PLQY \frac{J_G}{J_{0,rad}}\right)$$

QFLS denotes the energy difference between the electron and hole quasi-Fermi levels within the perovskite layer. k_B is the Boltzmann constant, and T represents the temperature (set at 300 K). J_G , the generation current density under illumination, is approximated by the device's short-circuit current density J_{SC} . $J_{0,rad}$ stands for the dark-radiative recombination saturation current density. According to the detailed balance at open-circuit conditions, the $J_{0,rad}$ can be calculated by the following equations:

$$J_{0,rad} = e \int_0^{\infty} EQE_{PV}(E) \Phi_{BB}(E) dE$$

$$\Phi_{BB}(E) = \frac{2\pi E^2}{h^3 c^2} \cdot \frac{1}{\exp\left(\frac{E}{k_B T}\right) - 1}$$

In the relevant calculations, e is the elementary charge, EQE_{PV} represents the photovoltaic external quantum efficiency, E denotes photon energy, $\Phi_{BB}(E)$ is the black-body radiative spectrum, h is Planck's constant, and c is the speed of light in vacuum. When the inverted PSCs reach equilibrium with black-body (BB) radiation at

$T = 300\text{K}$, the external quantum efficiency (EQE) of the devices and the emitted spectral photon flux are computed. Then, by combining this with the photoluminescence quantum yield (PLQY) of samples with different passivators, the QFLS of the samples can be derived via a corresponding equation.

Supplementary Note 4

Assessment of perovskite thin film decomposition via XRD

To assess the decomposition of the perovskite films, the formation of PbI_2 was analyzed using XRD. A decomposition index (K) was calculated based on the relative change in PbI_2 diffraction peak intensity before and after aging. First, the ratio R of the integral value of the PbI_2 peak to that of the reference perovskite (100) peak is determined for each sample:

$$R = \frac{I_{(\text{PbI}_2)}}{I_{(100)}}$$

where I denote the integrated intensity of the respective diffraction peak. The decomposition index K is subsequently given by:

$$K = \frac{R_{(\text{Aged})}}{R_{(\text{Fresh})}}$$

In these equations, the subscripts fresh and aged denote the as-prepared and aged samples, respectively.

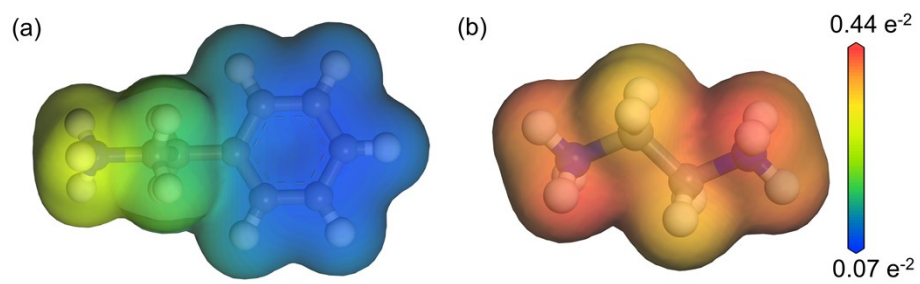


Figure S1. Calculated electrostatic potential (ESP) profiles of (a) PEA⁺ and (b) EDA²⁺ cations. The colour bar represents the fluctuation value of the ESP.

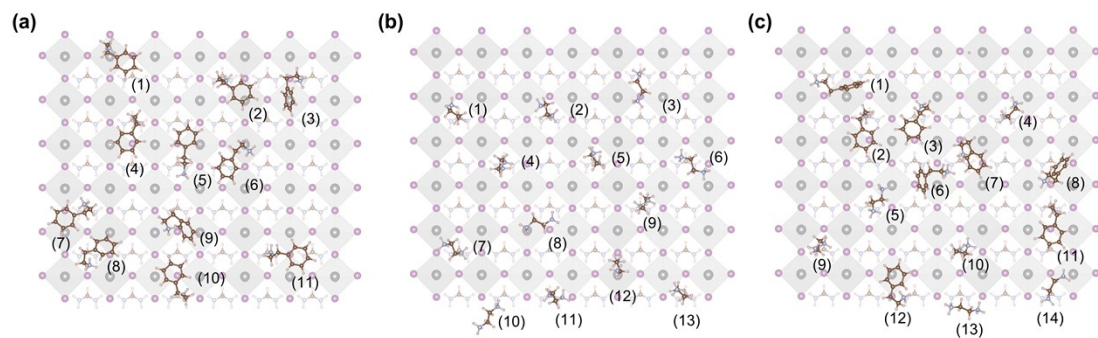


Figure S2. DFT-calculated top-view images of the perovskite surface with different passivators: (a) ParaC, (b) PerpC, and (c) OrthBC.

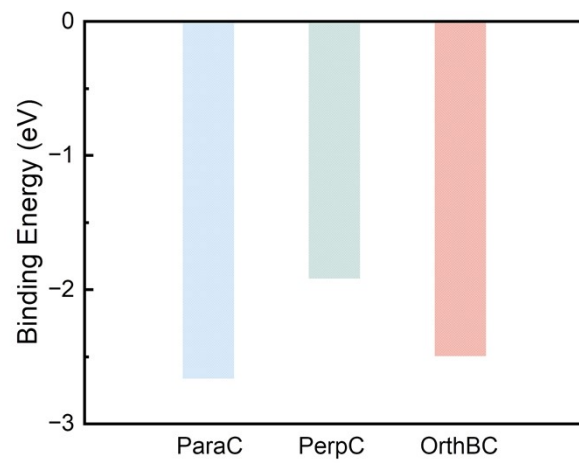


Figure S3. Binding energies of perovskite with different passivators.

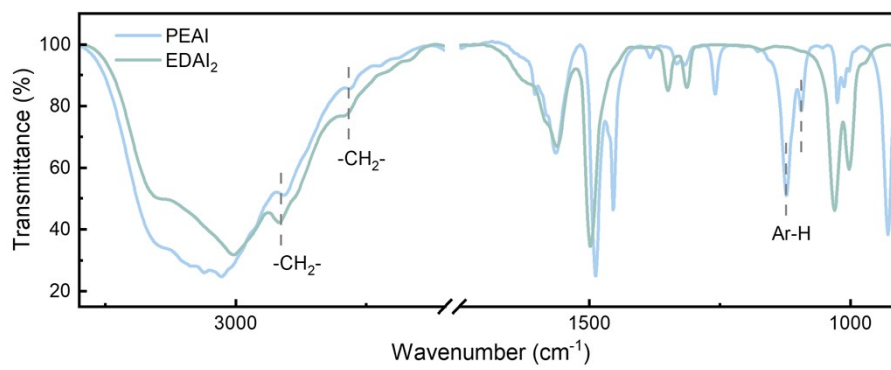


Figure S4. FTIR spectra of PEAI and EDAI₂ powders.

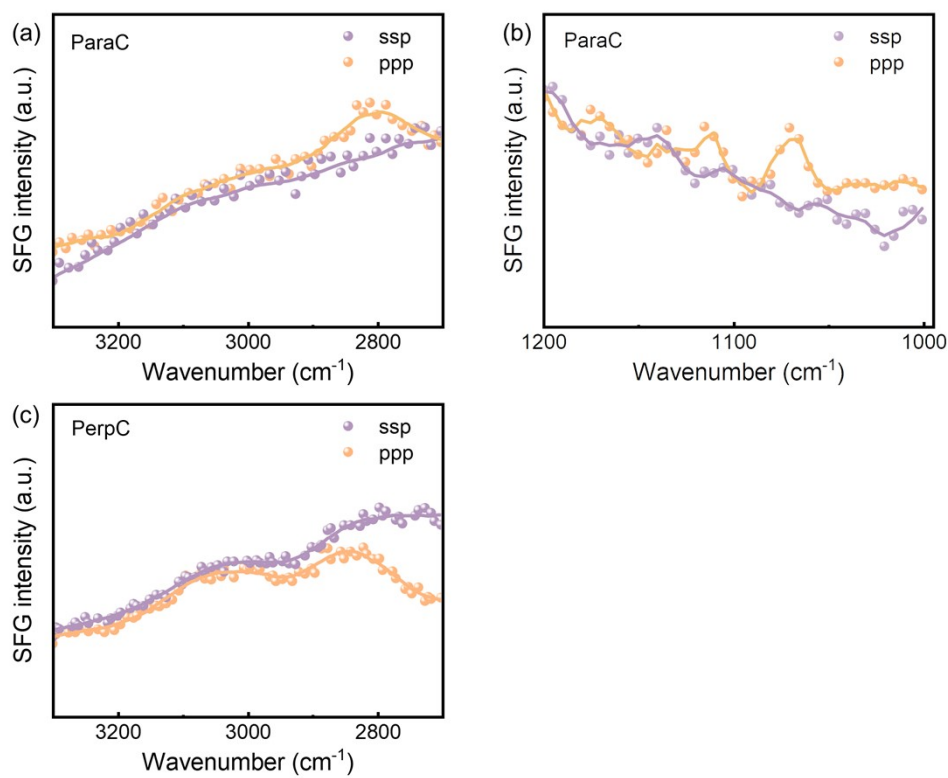


Figure S5. SFG spectra and corresponding fitting curves of perovskite film treated with (a, b) ParaC and (c) PerpC, respectively.

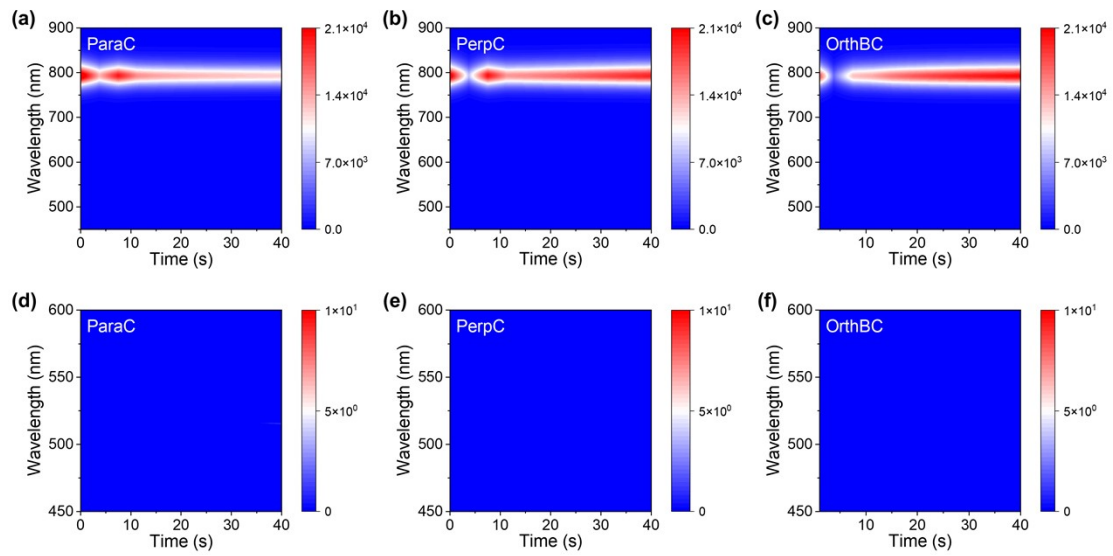


Figure S6. In situ PL intensity evolution of the perovskite films spin-coated with different passivators.

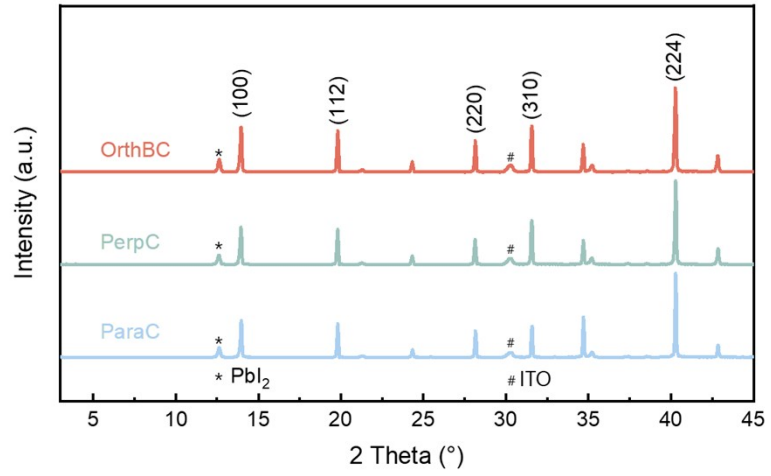


Figure S7. XRD patterns of perovskite films under different passivation strategies.

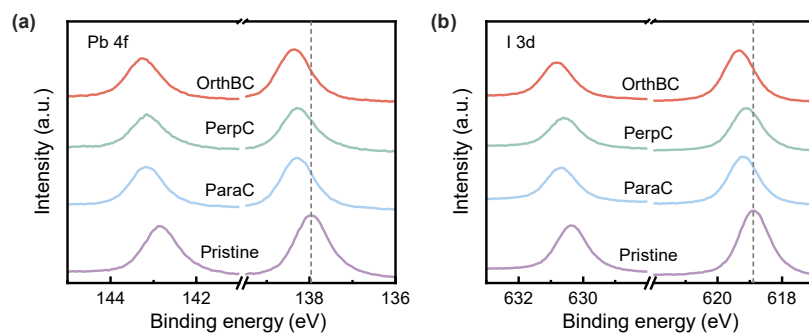


Figure S8. XPS core-level spectra of (a) Pb 4f and (b) I 3d for passivated perovskite films.

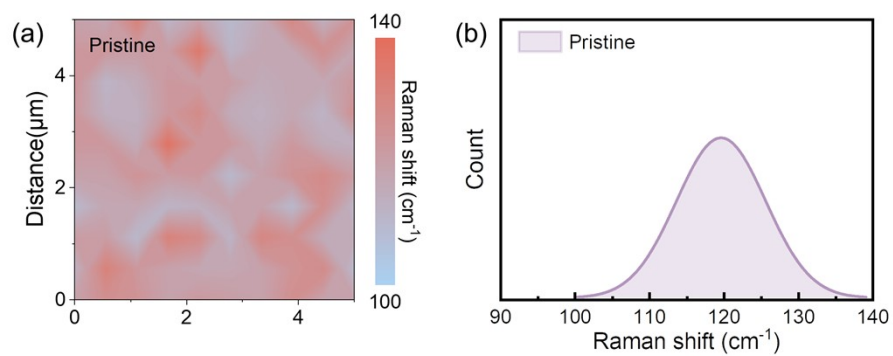


Figure S9. (a) Raman mapping for the Pb-I stretching vibration and (b) the corresponding spatial distribution analysis.

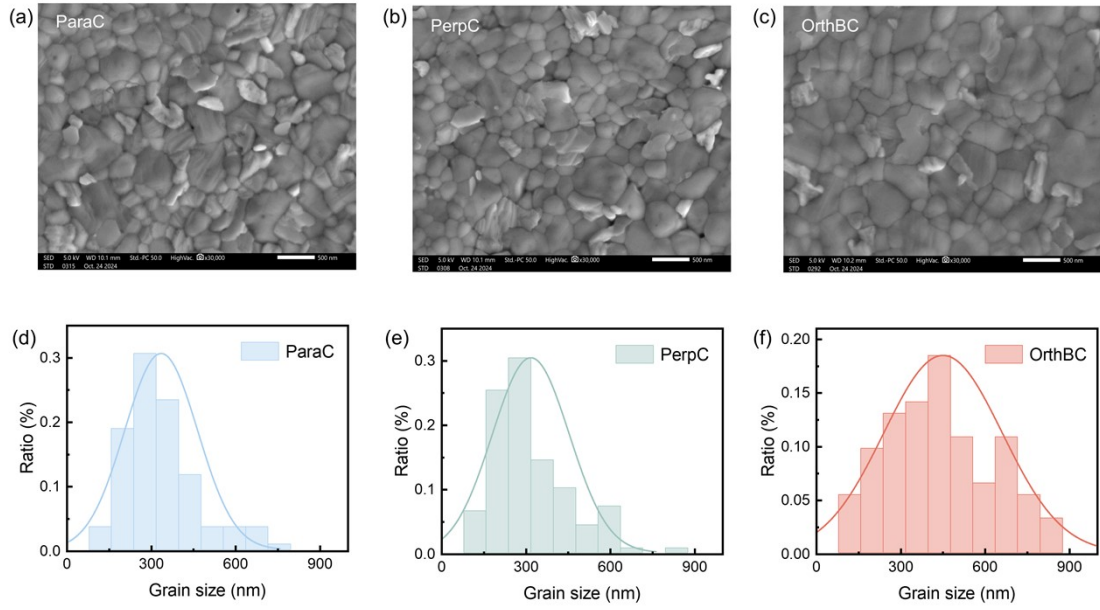


Figure S10. (a-c) top-view SEM images and (d-f) the quantitative analysis of grain size distribution for perovskite films with ParaC, PerpC, and OrthBC passivation.

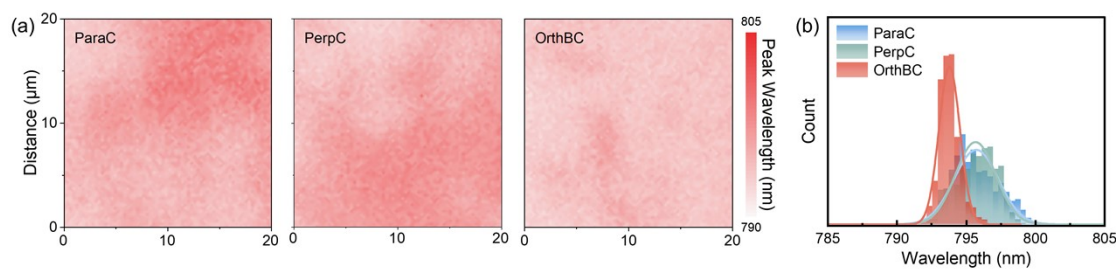


Figure S11. (a) PL wavelength mapping and (b) the corresponding statistical distribution.

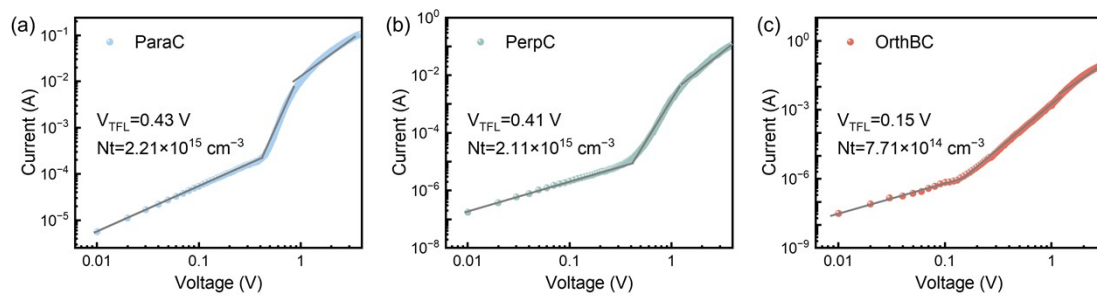


Figure S12. The space-charge-limited current (SCLC) measurements of electron-only devices based on perovskite films passivated with (a) ParaC, (b) PerpC, and (c) OrthBC.

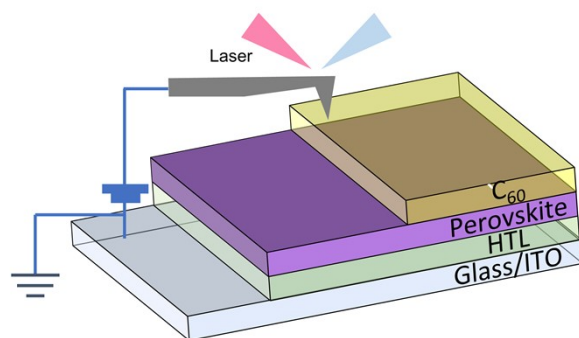


Figure S13. Schematic diagram of the KPFM setup used for measuring the surface potential of perovskite films that were partially covered with thermally evaporated C₆₀.

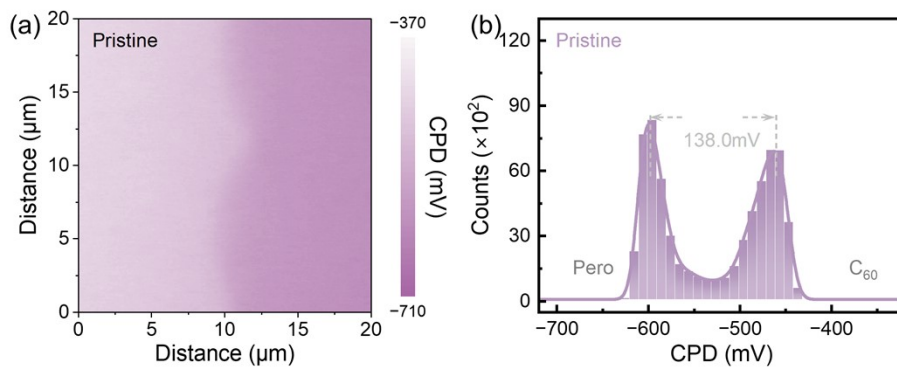


Figure S14. (a) KPFM potential images of perovskite/C₆₀ stack, along with corresponding (b) profiles of the surface potential distributions, the left region denotes the pristine perovskite, and the right region represents the C₆₀-coated perovskite.

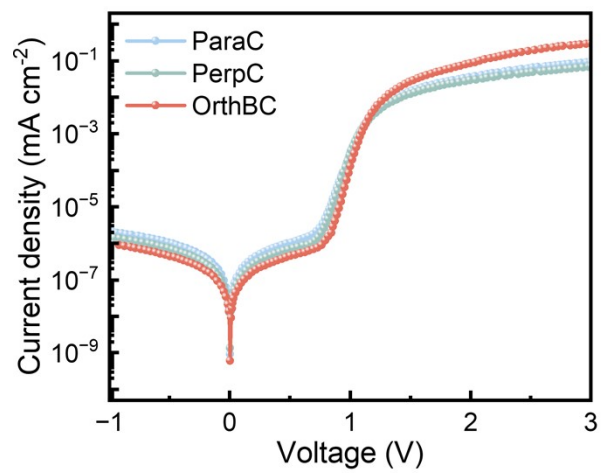


Figure S15. J - V curves of the devices measured under the dark condition.

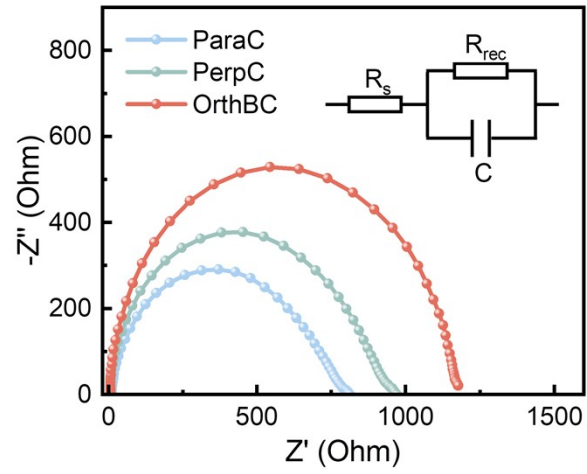


Figure S16. Nyquist plots of the devices. The inset is the equivalent circuit.

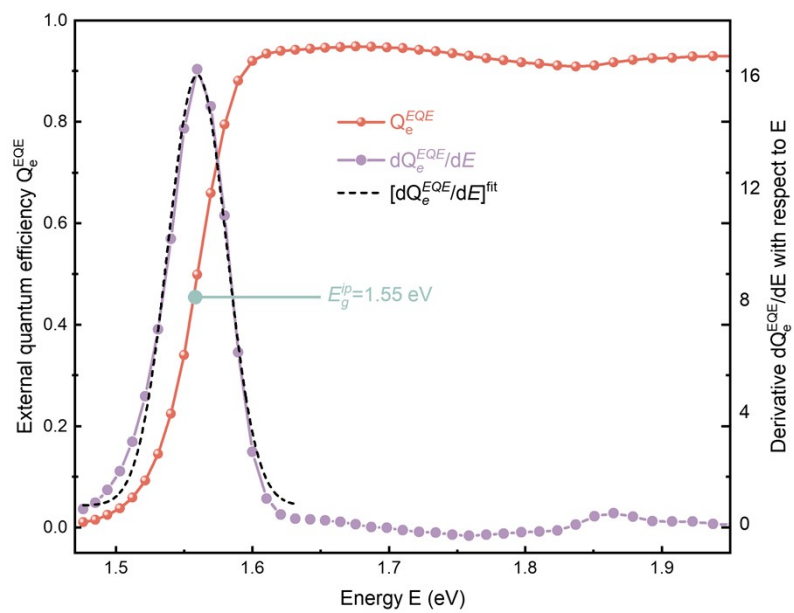


Figure S17. Analysis of the perovskite bandgap from the derivative of the EQE spectrum.⁴

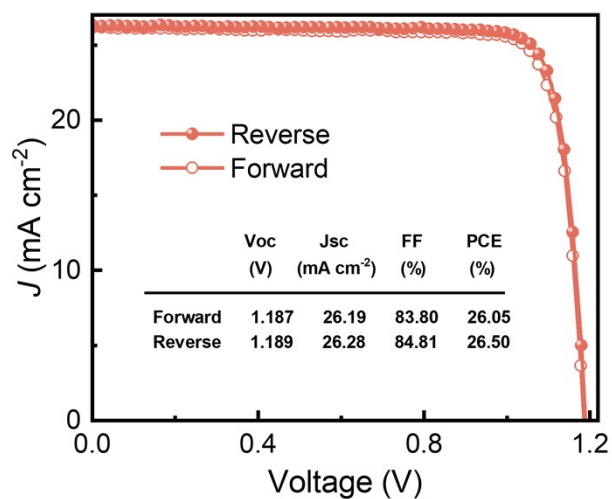


Figure S18. *J-V* curves of OrthBC devices under reverse and forward scan directions, with the corresponding measured PV parameters of the PSC included as an inset.

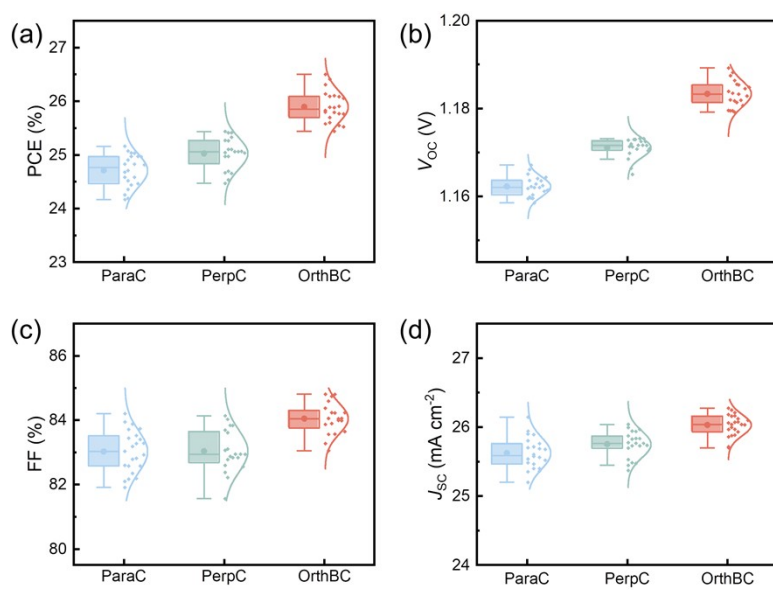


Figure S19. The statistical performance includes the PCE, V_{OC} , FF, and J_{SC} of the 0.09 cm^2 PSCs fabricated using the antisolvent method.

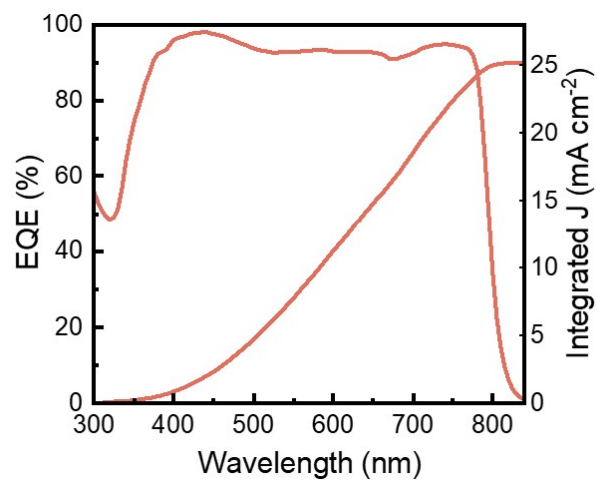


Figure S20. The EQE curves and the corresponding integrated photocurrent densities of the OrthBC-treated devices.

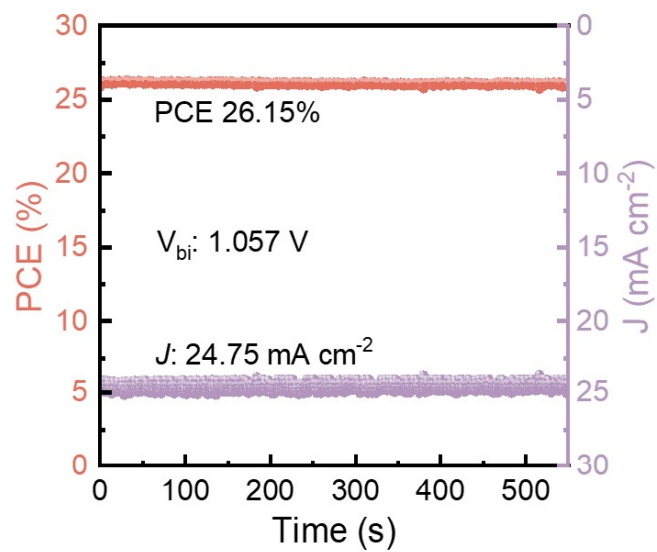


Figure S21. The stabilized power outputs were tested at the maximum power point of the OrthBC-treated devices.

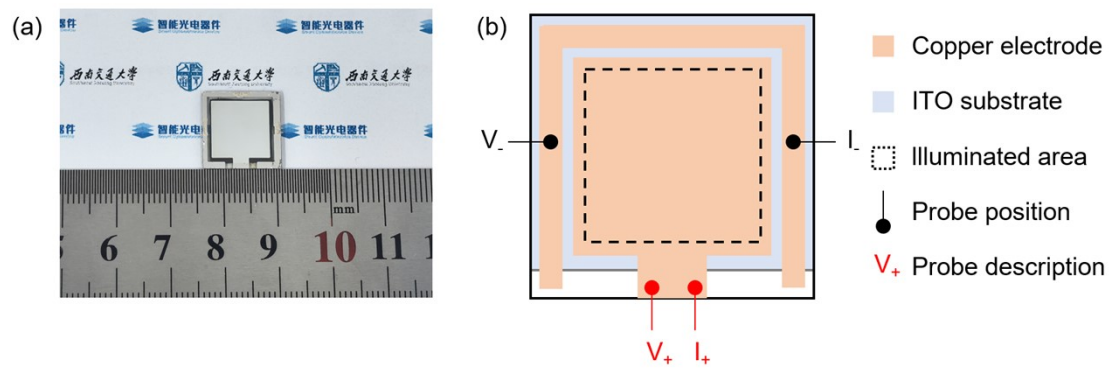


Figure S22. (a) Device with an effective area of 1.00 cm². (b) Schematic diagram of the four-wire measurement structure for the devices.

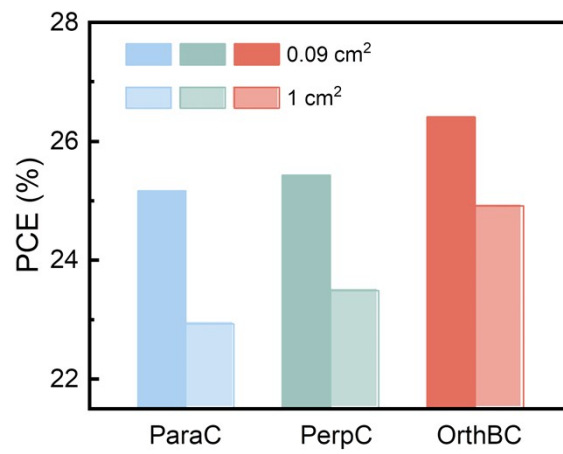


Figure S23. PCE comparison of devices with active areas of 0.09 cm² and 1.00 cm².

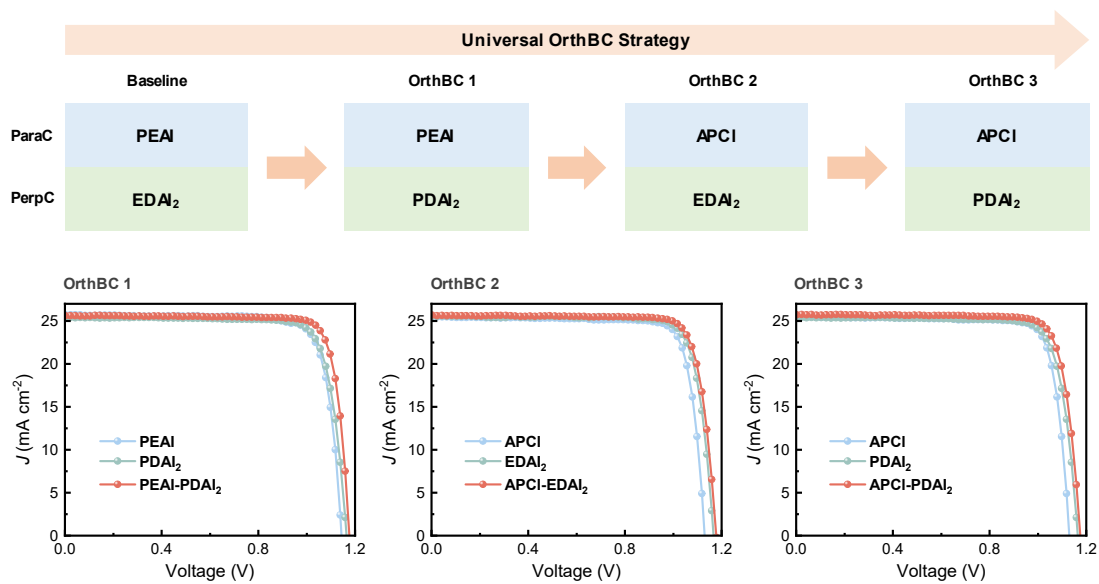


Figure S24. Universal applicability of the OrthBC strategy validated by *J-V* characteristics.

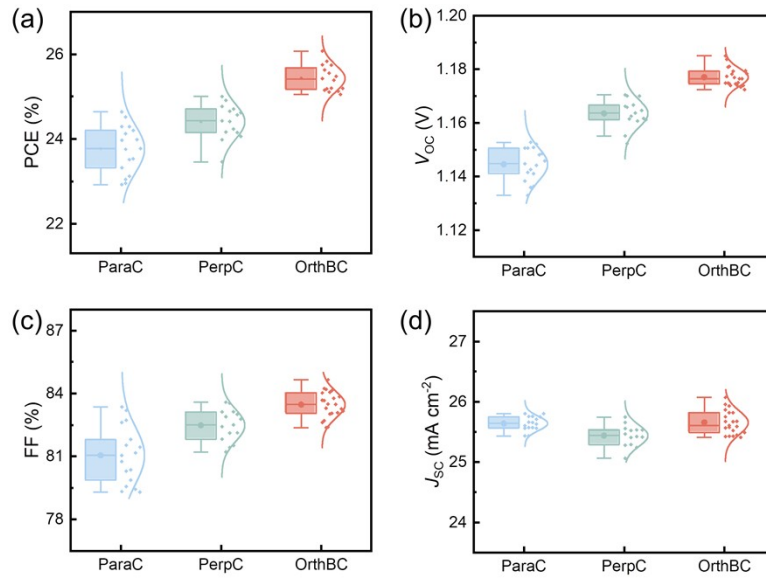


Figure S25. The statistical performance includes the PCE, V_{OC} , FF, and J_{SC} of the 0.09 cm² PSCs fabricated by sequential deposition.

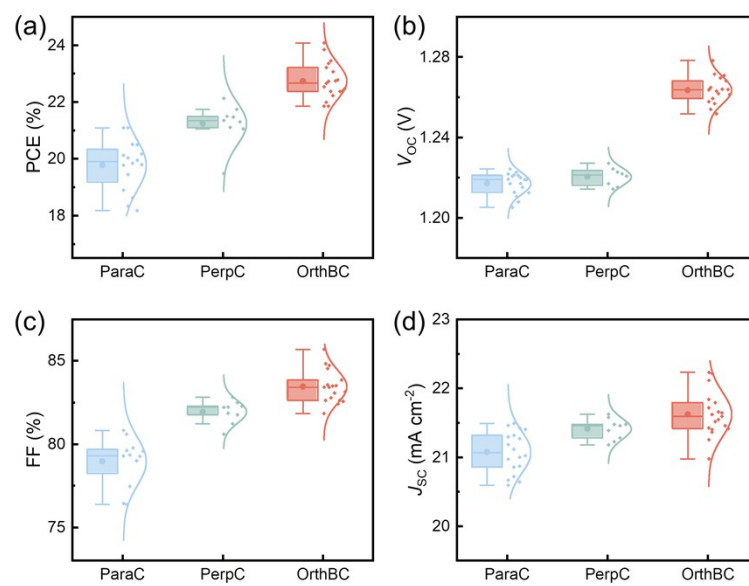


Figure S26. The statistical performance includes the PCE, V_{OC} , FF, and J_{SC} of the 1.68 eV-bandgap PSCs.

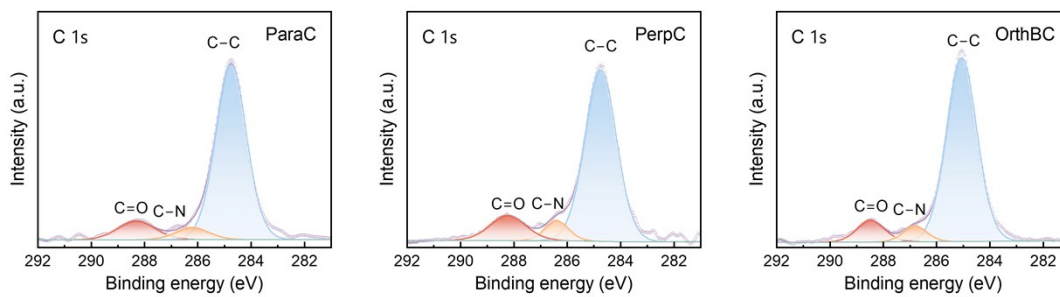


Figure S27. High-resolution C 1s XPS spectra of perovskite treated with different passivation strategies.

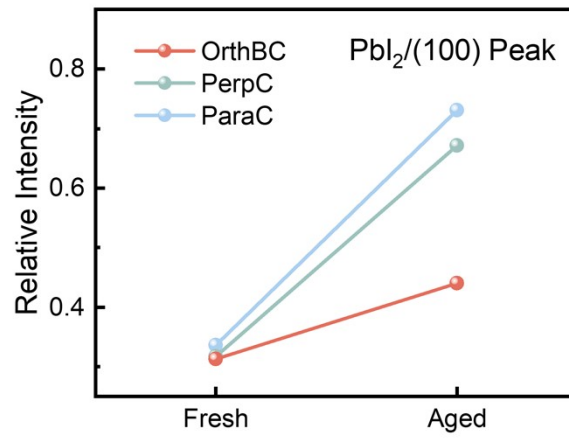


Figure S28. The ratio of the intensity of the PbI_2 peak to that of the (100) peak in the XRD pattern of the perovskite film.

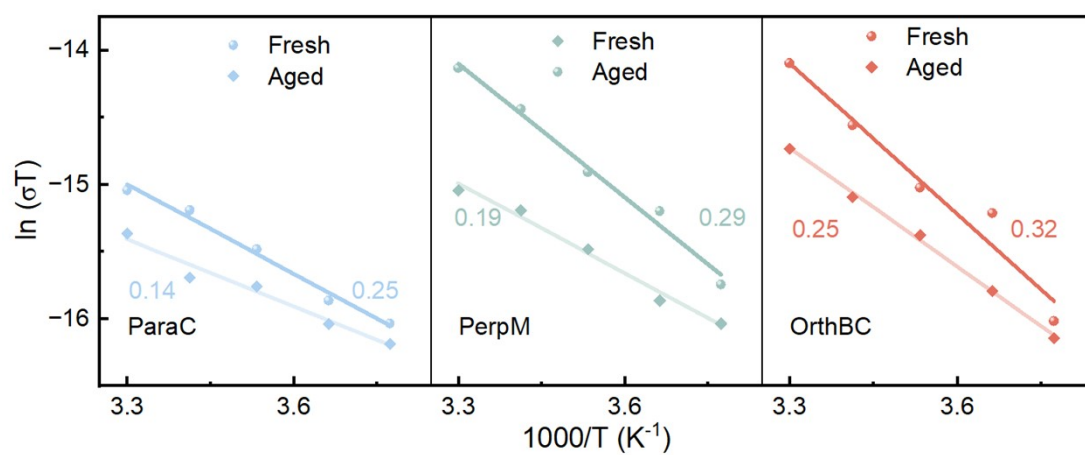


Figure S29. Nernst-Einstein plots of temperature-dependent conductivity for fresh and aged films, with the corresponding the E_a for ion migration indicated.

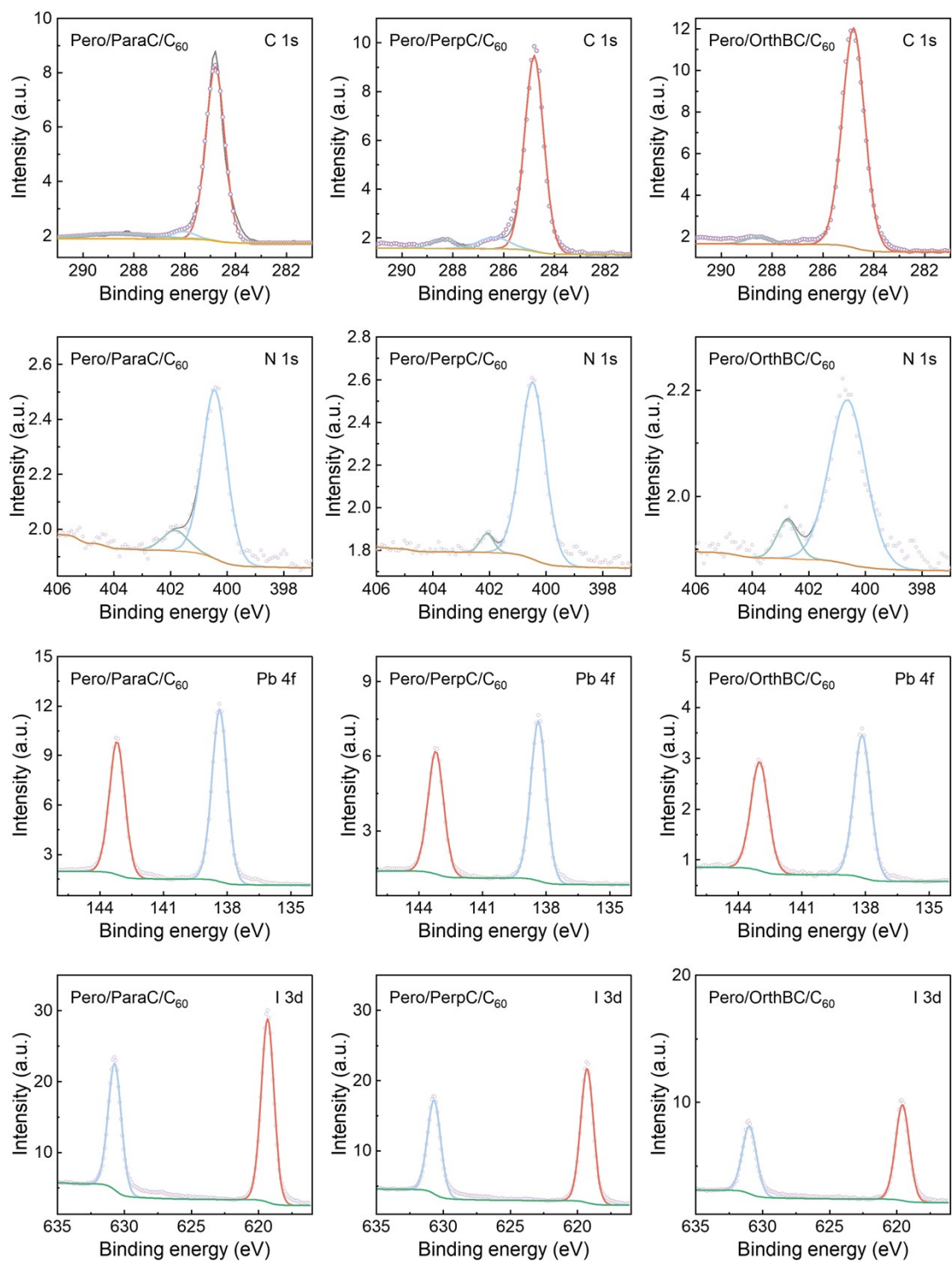


Figure S30. XPS core-level spectra of C 1s, N 1s, Pb 4f and I 3d for the perovskite/C₆₀ films with different passivation interlayers following thermal aging.

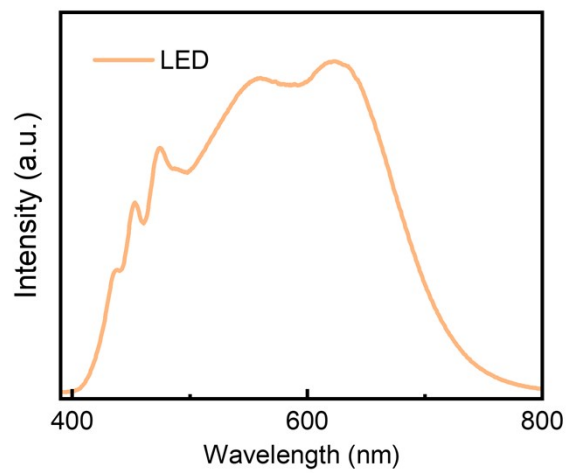


Figure S31. Spectral plot of the LED illumination for MPP tracking.

Table S1. The average chemical bond geometries (N–H···I length and angles) between amine groups and iodide ions.

Condition	ParaC		PerpC		OrthBC	
	length (Å)	angle (°)	length (Å)	angle (°)	length (Å)	angle (°)
all	3.01 ± 0.61	132.8 ± 19.5	2.78 ± 0.62	132.3 ± 17.52	2.99 ± 0.67	129.8 ± 20.6
Strong N–H···I	2.74 ± 0.44	143.3 ± 11.2	2.57 ± 0.28	137.0 ± 12.42	2.55 ± 0.44	143.5 ± 10.2

Table S2. XPS fitting peak positions of Pb 4f and I 3d in the pristine, ParaC, PerpC, and OrthBC-modified perovskite films.

Condition	Pb 4f _{7/2}	Pb 4f _{5/2}	I 3d _{3/2}	I 3d _{5/2}
pristine	137.91	142.80	618.83	630.29
ParaC	138.25	143.13	619.18	630.65
PerpC	138.21	143.09	619.07	630.53
OrthBC	138.32	143.20	619.27	630.75

Table S3. TRPL parameters of ParaC, PerpC, and OrthBC-modified perovskite films with C₆₀ and without C₆₀.

Condition	A ₁ (%)	τ ₁ (μs)	A ₂ (%)	τ ₂ (μs)	τ _{avg.} (μs)
ParaC	50.2	1.24	49.8	5.52	3.37
PerpC	47.5	1.44	52.5	5.63	3.64
OrthBC	23.8	2.08	76.5	5.81	4.93
ParaC/C ₆₀	47.3	1.03	52.7	5.17	3.21
PerpC/C ₆₀	54.5	1.06	45.5	5.04	2.87
OrthBC/C ₆₀	62.1	0.95	37.8	4.89	2.44

Table S4. The PV performance parameters of the 0.09 cm² device fabricated via the antisolvent method.

Condition	V_{OC} (V)	J_{SC} (mA cm ⁻²)	FF (%)	PCE (%)
ParaC	1.162	25.80	83.94	25.16
	1.162 ± 0.002	25.62 ± 0.22	83.02 ± 0.64	24.71 ± 0.3
PerpC	1.173	25.94	83.61	25.43
	1.171 ± 0.002	25.75 ± 0.19	83.04 ± 0.64	25.03 ± 0.28
OrthBC	1.189	26.28	84.81	26.50
	1.183 ± 0.003	26.03 ± 0.15	84.05 ± 0.47	25.89 ± 0.28

Table S5. The PV performance parameters of the 1-cm² devices.

Condition	V_{OC} (V)	J_{SC} (mA cm ⁻²)	FF (%)	PCE (%)
ParaC	1.144	25.21	79.52	22.93
	1.142 ± 0.004	25.13 ± 0.17	78.09 ± 0.76	22.44 ± 0.38
PerpC	1.164	25.18	80.58	23.49
	1.162 ± 0.005	24.95 ± 0.17	78.58 ± 0.81	22.79 ± 0.29
OrthBC	1.175	25.31	83.79	24.91
	1.176 ± 0.002	25.4 ± 0.09	82.5 ± 0.88	24.65 ± 0.19

Table S6. Photovoltaic parameters highlighting the universal OrthBC strategy.

Universality	Strategy	Molecules	V_{OC} (V)	J_{SC} (mA cm ⁻²)	FF (%)	PCE (%)
OrthBC 1	ParaC	PEAI	1.144	25.71	81.54	23.98
	PerpC	PDAI ₂	1.165	25.40	81.60	24.15
	OrthBC	PEAI-PDAI ₂	1.177	25.60	84.25	25.39
OrthBC 2	ParaC	APCI	1.130	25.51	82.96	23.92
	PerpC	EDAI ₂	1.167	25.52	82.51	24.56
	OrthBC	APCI-EDAI ₂	1.178	25.67	83.02	25.11
OrthBC 3	ParaC	APCI	1.130	25.51	82.96	23.92
	PerpC	PDAI ₂	1.165	25.40	81.60	24.15
	OrthBC	APCI-PDAI ₂	1.176	25.72	82.81	25.04

Table S7. The PV performance parameters of the 0.09 cm² device were fabricated by sequential deposition.

Condition	V_{OC} (V)	J_{SC} (mA cm ⁻²)	FF (%)	PCE (%)
ParaC	1.148 1.145 ± 0.006	25.75 25.64 ± 0.11	83.36 81.05 ± 1.32	24.67 23.76 ± 0.54
PerpC	1.170 1.163 ± 0.005	25.74 25.44 ± 0.17	83.01 82.48 ± 0.73	25.00 24.41 ± 0.39
OrthBC	1.185 1.177 ± 0.003	26.07 25.65 ± 0.19	84.38 83.47 ± 0.62	26.07 25.43 ± 0.30

Table S8. Photovoltaic parameters of the device with a bandgap of 1.68 eV.

Condition	V_{OC} (V)	J_{SC} (mA cm ⁻²)	FF (%)	PCE (%)
ParaC	1.221 1.217 ± 0.005	21.49 21.07 ± 0.29	80.34 78.96 ± 1.39	21.08 19.77 ± 0.86
PerpC	1.234 1.22 ± 0.004	21.85 21.41 ± 0.14	82.71 81.94 ± 0.64	22.31 21.23 ± 0.69
OrthBC	1.264 1.263 ± 0.007	22.23 21.57 ± 0.32	85.70 83.30 ± 0.113	24.07 22.73 ± 0.61

Table S9. Reported photovoltaic parameters of 1.65-1.69 eV bandgap perovskite solar devices: literature vs. our work.

Bandgap (eV)	Device structure	PCE (%)	V_{OC} (V)	FF (%)	J_{SC} (mA cm ⁻²)	Ref.
1.68	ITO/NiO _x /Me-2PACz/Cs _{0.05} FA _{0.8} MA _{0.15} Pb(I _{0.76} Br _{0.24}) ₃ /OrthBC/C ₆₀ /BCP/Ag	24.07	1.264	85.70	22.23	Our work
1.66	FTO/NiO _x /BTSA/Cs _{0.05} MA _{0.15} FA _{0.8} Pb(I _{0.76} Br _{0.24}) ₃ /C ₆₀ /BCP/Ag	24.50	1.314	84.64	22.03	19
1.65	ITO/MeO-2PACz/PTAA/MHy _{0.05} Cs _{0.2} FA _{0.75} Pb(I _{0.82} Br _{0.15} Cl _{0.03}) ₃ /C ₆₀ /BCP/Cu	23.30	1.28	83.8	21.8	20
1.67	FTO/MeO-2PACz/Cs _{0.05} (FA _{0.77} MA _{0.23}) _{0.95} Pb(I _{0.77} Br _{0.23}) ₃ /MHI/PCBM/BCP/Ag	23.25	1.28	83.06	21.87	21
1.67	ITO/NiO _x /Me-4PACz/Cs _{0.07} FA _{1.12} MA _{0.21} Pb(I _{0.77} Br _{0.23}) ₃ /CF ₃ -PEAI/LiF/C ₆₀ /BCP/Ag	23.20	1.267	85.1	21.52	22
1.67	/ITO/NiO _x /Me-4PACz/Cs _{0.22} FA _{0.78} Pb(I _{0.85} Br _{0.15}) ₃ /C ₆₀ /BCP/Ag	23.07	1.23	83.76	21.46	23
1.67	ITO/4PADCB/FA _{0.8} Cs _{0.15} MA _{0.05} PbI _{2.4} Br _{0.6} /PDAI/C ₆₀ /BCP/Cu	23.05	1.246	85.34	21.68	24
1.68	ITO/NiO _x /MeO-2PACz/Cs _{0.1} FA _{0.9} Pb(I _{0.83} Br _{0.17}) ₃ /CF ₃ -PEAI/C ₆₀ /BCP/Ag	22.95	1.277	84.08	21.37	25
1.68	ITO/2PACz/Cs _{0.05} (FA _{0.77} MA _{0.23}) _{0.95} Pb(I _{0.77} Br _{0.23}) ₃ /LiF/C ₆₀ /SnO ₂ /Ag	22.87	1.24	84.67	21.76	26
1.68	ITO/MeO-4PACz:Nd ³⁺ /Cs _{0.05} (FA _{0.77} MA _{0.23}) _{0.95} Pb(I _{0.77} Br _{0.23}) ₃ /PEAI/PC ₆₀ BM/BCP/Ag	22.82	1.212	86.35	21.8	27
1.68	FTO/NiO _x /Me-4PACz/Cs _{0.17} FA _{0.83} Pb(I _{0.83} Br _{0.17}) ₃ /C ₆₀ /SnO ₂ /Ag	22.80	1.286	83.89	21.12	28
1.68	ITO/NiO _x /MeO-2PACz/Cs _{0.1} FA _{0.9} Pb(I _{0.83} Br _{0.17}) ₃ /C ₆₀ /BCP/Ag	22.74	1.277	84.08	21.37	29
1.67	ITO/4-PhCz/Cs _{0.17} FA _{0.83} Pb(I _{0.8} Br _{0.2}) ₃ /C ₆₀ /BCP/Ag	22.53	1.273	83.21	21.27	30
1.68	ITO/SnO ₂ /Cs _{0.05} (FA _{0.77} MA _{0.23}) _{0.95} Pb(I _{0.77} Br _{0.23}) ₃ /PTAA/Au	22.32	1.24	80.14	22.39	26
1.68	ITO/MeO-2PACz/Cs _{0.05} (FA _{0.77} MA _{0.23}) _{0.95} Pb(I _{0.77} Br _{0.23}) ₃ /PCI/C ₆₀ /BCP/Ag	22.30	1.254	85.6	20.3	31
1.68	FTO/NiO _x /Me-4PACz/2DPAA/Cs _{0.05} (FA _{0.77} MA _{0.23}) _{0.95} Pb(I _{0.77} Br _{0.23}) ₃ /PDADI/C ₆₀ /BCP/Ag	22.02	1.24	81.51	21.82	32
1.65	ITO/TiO ₂ -SnO ₂ /FA _{0.5} Cs _{0.5} Pb(I _{0.93} Br _{0.07}) ₃ /Spiro-OMeTAD/Ag	21.94	1.27	82.36	20.99	33
1.67	ITO/Poly-TPD/Cs _{0.2} FA _{0.8} Pb(I _{0.82} Br _{0.15} Cl _{0.03}) ₃ /C ₆₀ /RPD-ITO/Ag	21.80	1.242	82.57	21.26	34
1.69	ITO/NiO _x /Me-4PACz/Cs _{0.45} FA _{0.55} Pb(I _{0.85} Br _{0.15}) ₃ /C ₆₀ /SnO ₂ /Ag	21.37	1.174	84.08	21.65	35
1.66	FTO/Me-4PACz/Cs _{0.24} FA _{0.76} Pb(I _{0.8} Br _{0.2}) ₃ /C ₆₀ /BCP/Ag	20.10	1.201	80.6	20.76	36

Table S10. Atomic percentages and chemical bond ratios of perovskite films with different passivators, derived from XPS analysis.

Condition	C-C (%)	C-N (%)	C=O (%)	N (%)	Pb (%)	I (%)
ParaC	50.08	3.65	6.54	9.26	22.55	7.92
PerpC	46.98	4.07	7.84	11.47	22.29	7.35
OrthBC	51.06	3.34	5.41	10.44	22.33	7.42

Table S11. Surface atomic ratios of the perovskite/C₆₀ films with different passivation interlayers following thermal aging.

	Area (CPS·eV)				Atomic (%)			
	C 1s	N 1s	Pb 4f	I 3d	C 1s	N 1s	Pb 4f	I 3d
ParaC	69991	7621	173239	543468	74.61	4.96	5.35	15.07
PerpC	87673	9808	107422	404448	81.69	5.60	2.90	9.80
OrthBC	121652	5752	51249	172788	92.75	2.69	1.13	3.42

Table S12. Performance and stability data of perovskite solar devices with molecular orientation passivation are derived from previous literature and this work.

Architecture	PCE (%)	Molecular Orientation	Aging and Retention	Ref.
Inverted	26.50	OrthBC	ISOS-D-2: 93.9% /1300 h ISOS-L-2I, MPP: 91.2% /1000 h	Our work
Inverted	25.64	ParaC	ISOS-D-2I: 80% /900 h ISOS-L-1I, MPP: 97% /900 h	5
Inverted	22.20	ParaC	ISOS-D-1: 82% /1250 h ISOS-L-1I, MPP: 80% /1200 h	6
Inverted	24.20	PerpC	ISOS-D-1: 64% /192 h ISOS-L-1, MPP: 92% /240 h	7
Normal	25.76	ParaC	ISOS-D-1: 90.8% /1000 h	8
Inverted	25.45	PerpC	ISOS-D-2: 90% /1000 h ISOS-L-1I, MPP: 100% /3000 h	9
Inverted	25.79	ParaC	ISOS-D-1: 95% /1200 h ISOS-L-1I, MPP: 91% /1200 h	10
Inverted	24.08	ParaC	ISOS-D-2I: 82% /500 h ISOS-L-1I, MPP: 95% /500 h	11
Normal	19.20	PerpC	ISOS-D-2: 50% /2880 h	12
Inverted	24.87	ParaC	ISOS-D-1I: 97% /1800 h ISOS-D-2I: 90% /1200 h	13
Inverted	26.32	ParaC	ISOS-D-1: 90% /1000 h ISOS-L-1I, MPP: 95.8% /2000 h	14
Inverted	22.12	ParaC	ISOS-D-1I: 95% /1600 h ISOS-L-1, MPP: 97% /360 h	15
Inverted	25.83	PerpC	ISOS-D-1: 88% /1000 h ISOS-L-1I, MPP: 92% /680 h	16
Normal	24.70	PerpC	ISOS-D-1: 95% /1440 h	17
Inverted	22.10	PerpC	ISOS-D-1: 90% /500 h ISOS-L-1I: 80% /750 h	18

Note: ISOS-D-1: Dark storage at room temperature under ambient laboratory conditions. ISOS-D-2: Dark storage at 65 °C under ambient laboratory conditions. ISOS-L-1I: Continuous 1-sun illumination at room temperature. ISOS-L-2I: Continuous 1-sun illumination at 65 °C. The suffix “I” denotes testing in an inert environment. MPP refers to the maximum power point when a bias voltage is applied.

Table S13. A summary of the mixed-cation passivation or multifunctional strategies, underlying mechanisms, and the device performance.

Year	Mechanism	Molecule 1	Molecule 2	PCE	Device Stability	Ref.
2026	Orthogonal binary cation	Phenethylammonium iodide	Ethylenediamine dihydroiodide	26.50% 24.91%*	Retained 91.2% after 1000 h (ISOS-D-2) Retained 93.9% after 1000 h (MPP, 65°C)	This work
2026	Bimolecular co-anchoring strategy	4-[3-(Trifluoromethyl)-3H-diazirin-3-yl]benzoic acid	2-Benzamidinyl-5-guanidinopentanoic acid	26.07%	Retained 95.0% after 1300 h (85°C) Retained 91.0% after 1500 h (MPPT)	37
2025	Deprotonation-resistant passivation	N,N-Dimethylbenzenesulfonamide	Phenethylammonium iodide	25.43%	Retained 96.1% after 1500 h (85°C)	38
2024	Phase-pure regulation	3,6-Dimethyl-carbazole-9-ethylammonium iodide	m-Fluorophenylethylammonium iodide	25.86% 25.08%*	Retained 90.0% after 1000 h (MPP)	39
2024	Molecular packing optimization	4-tert-Butylbenzylammonium iodide	Phenylpropylammonium iodide	26.00%	Retained 81.0% after 450 h (MPP)	40
2024	Kinetic competition control	Phenylmethylammonium iodide	Octylammonium iodide	25.23%	Retained 88.0% after 1000 h (MPP)	41
2023	Ion-diffusion management	Octylammonium iodide	Guanidinium chloride	25.43%	Retained 83.0% after 1200 h (MPP)	42
2023	Chemical and field-effect passivation	Propane-1,3-diammonium iodide	3-(Methylthio)propylamine hydroiodide	25.10%	Retained stability for >2000 h (65°C)	43

Note: *Device with 1.00 cm²; ISOS: International Summit on Organic Photovoltaic Stability; ISOS-D-2: dark storage at 65°C; ISOS-L-2I: light soaking at 65°C; MPP: maximum power point.

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